

Substitute for Form 1449 A & B/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(use as many sheets as necessary)</i>				Complete if Known	
				Application Number	10/765,904
				Confirmation Number	2613
				Filing Date	January 29, 2004
				First Named Inventor	Markus MENGEL
				Art Unit	Not Yet Assigned
Examiner Name	Not Yet Assigned				
Attorney Docket Number	Q79656				
Sheet	1	of	1		

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
		Number	Kind Code ² (if known)		
SAT		US 6,473,176	B1	10/29/2002	Wang, et al.
		US 6,473,181	B1	10/29/2002	Oakberg
		US 5,886,810		03/23/1999	Siahpoushan, et al.
		US 5,744,721		04/28/1998	Varnum
		US 5,652,673		07/29/1997	Oakberg
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FOREIGN PATENT DOCUMENTS							
Examiner Initials*	Cite No. ¹	Foreign Patent Document			Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Translation ⁶
		Country Code ³	Number ⁴	Kind Code ⁵ (if known)			

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city, and/or country where published.	Translation ⁶
SAT		H. P. POVEL et al., "Two-dimensional polarimeter with a charge-coupled-device image sensor and a piezoelectric modulator," Applied Optics, July 1, 1994, pp. 4254-4259, Vol. 33, No. 19	
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		D. WRÓBLEWSKI et al., "Polarimetry of motional Stark effect and determination of current profiles DIII-D (invited)," Rev. Sci. Instrum., October 1992, Vol. 63, No. 10	
		M. TOTZECK et al., "Edge localization of subwavelength structures by use of polarization interferometry and extreme-value criteria," Applied Optics, December 1, 2000, Vol. 39, No. 34	
		M. TOTZECK et al., "High-resolution inspection of 2D-microstructures using multi-mode polarization microscopy," Proceedings of the 2 nd Conference on Design and Fabrication, 2000, Japan	
SAT		D. CLARKE and J. F. GRAINGER, "Polarized Light and Optical Measurement," Pergamon Press, Oxford, 1971	

Examiner Signature	/Samuel A. Turner/	Date Considered	05/05/2006
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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IDS - 01/29/2004
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STATEMENT BY APPLICANT**

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Examiner Initials*	Cite No. ¹	Document Number		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
		Number	Kind Code ² (if known)		
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		US 5 396 329		3/7/1995	BRITISH AEROSPACE PLC
		US 5 298 972		3/29/1994	HEWLETT-PACKARD COMPANY
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		US 6 312 373	B1	11/6/2001	NIKON CORPORATION
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FOREIGN PATENT DOCUMENTS

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		Country Code ³	Number ⁴	Kind Code ⁵ (if known)			
SAT		DE	101 09 929	A1	11/22/2001	CARL ZEISS	
		EP	0 439 127	A2	7/31/1991	HEWLETT-PACKARD COMPANY	
		EP	0 396 409	A2	11/7/1990	THERMA-WAVE INC.	
		JP	11-142291	A	5/28/1999	NIKON CORPORATION	Abstract
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SAT		WO	03/028073	A1	4/3/2003	NIKON CORPORATION	Claims

NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city, and/or country where published.	Translation ⁶
SAT		"OPTICAL SHOP TESTING", EDITED BY: DANIEL MALACARA, JOHN WILEY & SONS, INC., SECOND EDITION, PAGES 112-113, 1992, USA.	
SAT		MICHAEL I. SHRIBAK ET AL, "RETURN-PATH POLARIMETER FOR TWO DIMENSIONAL BIREFRINGENCE DISTRIBUTION MEASUREMENT", JULY 1999, SPIE, PAGES 144-145 AND 148-149, VOLUME 3654, DENVER COLORADO	
SAT		S. BEREZHNA, ET AL, "ACCURACY OF WHOLE-FIELD MAPPING BY JONES MATRIX FOURIER PHOTOPOLARIMETER", 2000, PROCEEDINGS OF SPIE, PAGES 81-89, VOLUME 4148	

Examiner Signature /Samuel A. Turner/

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